Tester II commands and syntax (continued)

Overlay trap: OT[A | B | BA][C] [N=*nn*];

Overlay trap kill: OTK;

Print: P{*addr* | C};

Quit: QU;

Return: ;

Set FAC protection: FAC [*x*];

Simulator write: SW;

Stop: S[R] [P] { {*addr'data'* | *addr-range*$_1$ [+*addr-range*$_2$ [. . . +*addr-range*$_5$]]} [,N=*nnnn*] | i [S] };

Stop kill: SK;

full line display
write instructions
with line format

Trace: T [F | W | I | B | BI] [L | A | C] [*addr-range*$_1$ [+*addr-range*$_2$ [. . . +*addr-range*$_5$]] [B]];

7700/0

or: T M [L | A | C] *addr* [*addr*];

Trace kill: TK;

Up paper: U;

Workstation input: WS;

Note: Syntax for addr-range parameter: {*addr* [*addr*] | (*addr* [*addr*])}